Tencor Alpha-Step 200 Contact Profilometer

DESCRIPTION:
• For applications in thin or thick films
• Vertical ranges:
  160 kÅ (kilo Angstrom range)
  160 um (micrometer range)
• Horizontal range 10,000 µm
• Stylus force may be set as low as 1mg
• Can be used to measure samples up to 21mm thick (Z), 150mm (X), 81mm (Y)

LOCATION: IEEC RELIABILITY LAB

For more information or to arrange for the use of this equipment, contact any of the IEEC staff members listed below:

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